


<b>Search Notes</b>  	<b>Application/Control No.</b>  10800153	<b>Applicant(s)/Patent Under Reexamination</b>  WATANABE, HISAYUKI
	<b>Examiner</b>  Takele, Meseker	<b>Art Unit</b>  2175

SEARCHED			
Class	Subclass	Date	Examiner
715	810,741, 854,153	12/19/2009	MT
434	323	12/19/2009	MT
701	200, 208, 209	12/19/2009	MT

SEARCH NOTES		
Search Notes	Date	Examiner
East (US-PGPUB, USPAT, IBM-TDB, USOCR, FPRS, EPO, JPO, DERWENT)	12/19/2009	MT
Inventor search	6/22/2009	MT
Discussed with SY Luu	3/29/2008	MT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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